Simulation of the Double Peak Effect in irradiated Sensors

Thursday 31 May 2012 14:20 (20 minutes)

Following the RD50 Simulation Group proposal, simulations of the Double Peak Effect in irradiated sensors have been performed using the Synopsys TCAD Sentaurus software. Implementation of traps and modeling of leakage current will be explained in detail. The resulting electric field distribution and TCT signals at different voltages, fluences and temperatures are presented.

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